

## 20V N-Channel Enhancement-Mode MOSFET

LN2302LT1G

$V_{DS} = 20V$

$R_{DS(ON)}, V_{GS}@4.5V, I_{DS}@2.8A = 60m\Omega$

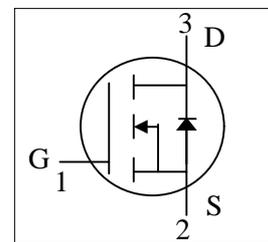
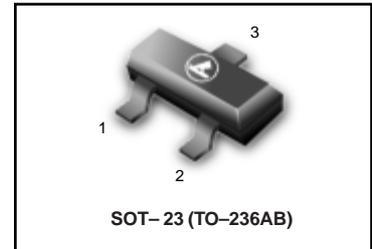
$R_{DS(ON)}, V_{GS}@2.5V, I_{DS}@2.0A = 115m\Omega$

### Features

High Density Cell Design For Ultra Low On-Resistance

Improved Shoot-Through FOM

we declare that the material of product compliance with RoHS requirements.



▼ High Density Cell Design For Ultra Low On - Resistance  
Improved Shoot-Through FOM

### Ordering Information

Device	Marking	Shipping
LN2302LT1G	N02	3000/Tape & Reel
LN2302LT3G	N02	10,000/Tape & Reel

### Maximum Ratings and Thermal Characteristics ( $T_A = 25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	$V_{DS}$	20	V	
Gate-Source Voltage	$V_{GS}$	$\pm 8$		
Continuous Drain Current	$I_D$	2.3	A	
Pulsed Drain Current <sup>1)</sup>	$I_{DM}$	8		
Maximum Power Dissipation	$P_D$	$T_A = 25^\circ C$	0.9	W
		$T_A = 75^\circ C$	0.57	
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 to 150	$^\circ C$	
Junction-to-Case Thermal Resistance	$R_{qJC}$		$^\circ C/W$	
Junction-to-Ambient Thermal Resistance (PCB mounted) <sup>2)</sup>	$R_{qJA}$	145		

Note: 1. Repetitive Rating: Pulse width limited by the Maximum junction temperature

2. 1-in<sup>2</sup> 2oz Cu PCB board

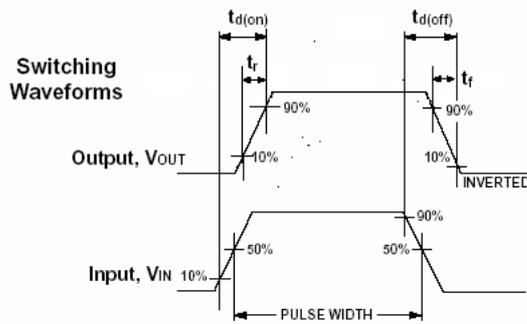
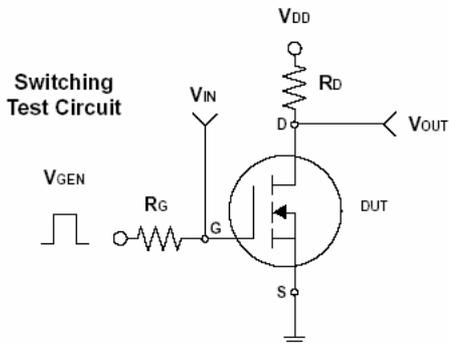
3. Guaranteed by design; not subject to production testing

# LN2302LT1G

## ELECTRICAL CHARACTERISTICS

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	20	-	-	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 2.8A$		40	60	mΩ
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 2.5V, I_D = 2.0A$		50	115	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	0.60	0.95	1.20	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 9.6V, V_{GS} = 0V$			-1	μA
Gate Body Leakage	$I_{GSS}$	$V_{GS} = \pm 8V, V_{DS} = 0V$			±100	nA
Gate Resistance	$R_g$					Ω
Forward Transconductance	$g_{fs}$	$V_{DS} = 5V, I_D = 4.0A$		6.5		S
<b>Dynamic <sup>3)</sup></b>						
Total Gate Charge	$Q_g$	$V_{DS} = 6V, I_D = 2.8A$ $V_{GS} = 4.5V$		3.69		nC
Gate-Source Charge	$Q_{gs}$			0.70		
Gate-Drain Charge	$Q_{gd}$			1.06		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 6V, R_L = 6\Omega$ $I_D = 1A, V_{GEN} = 4.5V$ $R_G = 6\Omega$		6.16		ns
Turn-On Rise Time	$t_r$			7.56		
Turn-Off Delay Time	$t_{d(off)}$			16.61		
Turn-Off Fall Time	$t_f$			4.07		
Input Capacitance	$C_{iss}$	$V_{DS} = 6V, V_{GS} = 0V$ $f = 1.0\text{ MHz}$		427.12		pF
Output Capacitance	$C_{oss}$			80.56		
Reverse Transfer Capacitance	$C_{rss}$			57.00		
<b>Source-Drain Diode</b>						
Max. Diode Forward Current	$I_S$				1.6	A
Diode Forward Voltage	$V_{SD}$	$I_S = -1.6A, V_{GS} = 0V$			1.2	V

Note: Pulse test: pulse width ≤ 300μs, duty cycle ≤ 2%



LN2302LT1G

TYPICAL ELECTRICAL CHARACTERISTICS

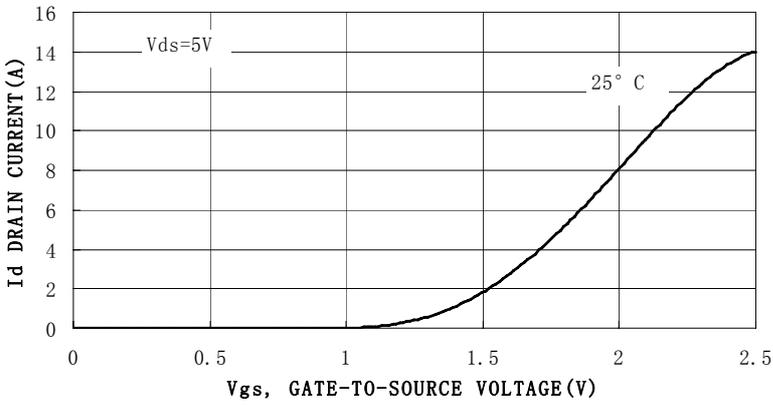


Figure 1. Transfer Characteristics

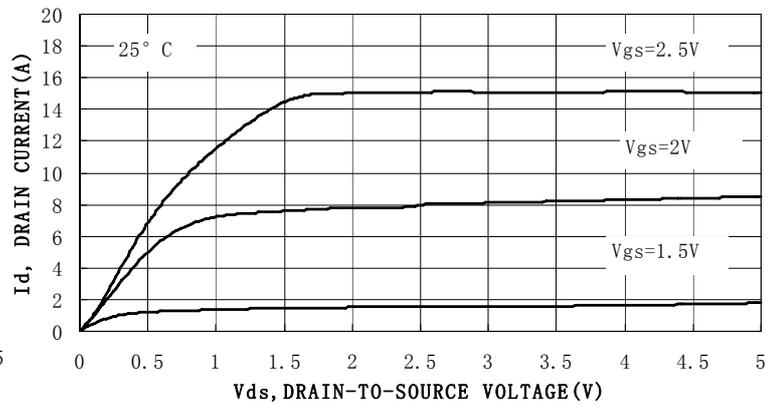


Figure 2. On-Region Characteristics

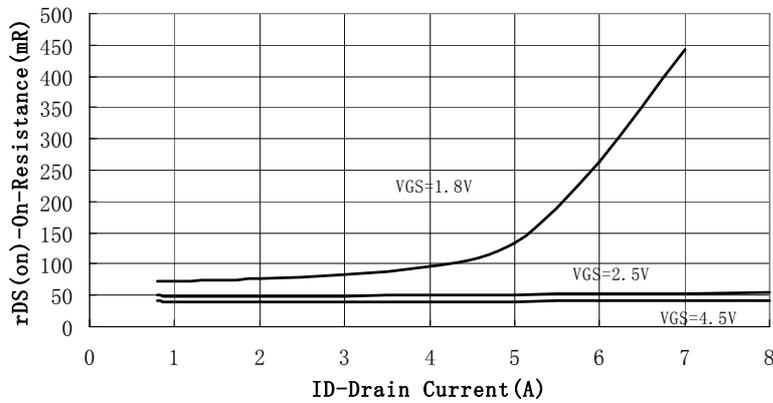


Figure 3. On-Resistance versus Drain Current

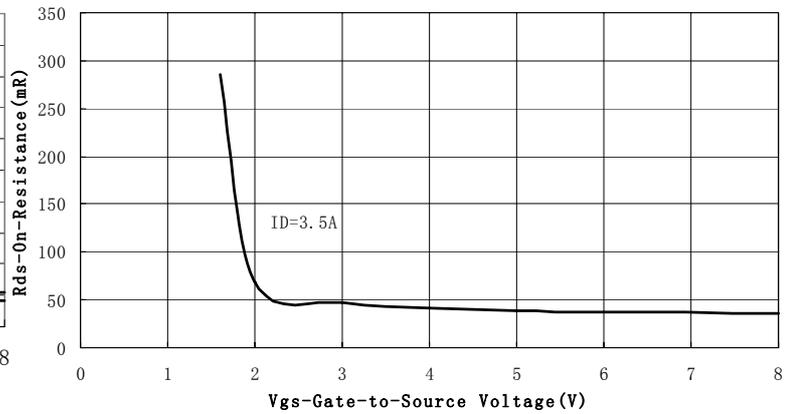


Figure 4. On-Resistance vs. Gate-to-Source Voltage

LN2302LT1G

TYPICAL ELECTRICAL CHARACTERISTICS

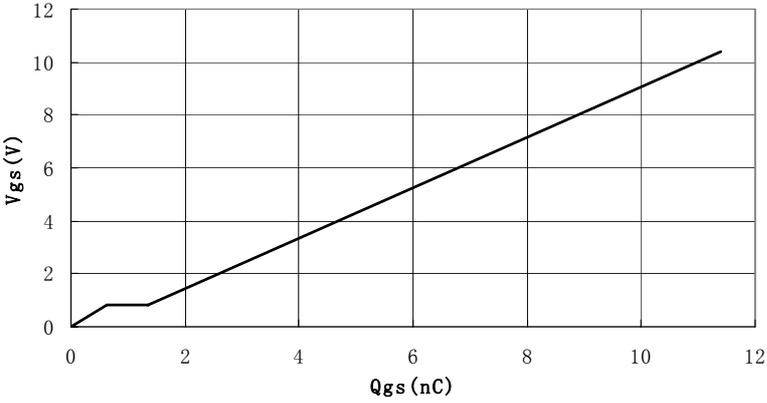


Figure 5. Gate Charge

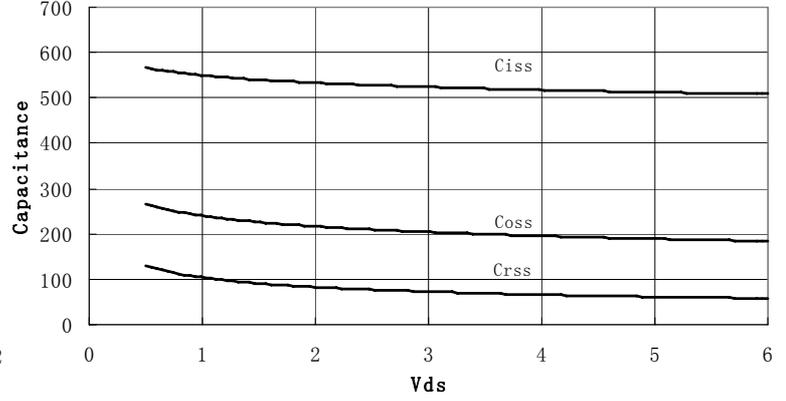


Figure 6. Capacitance

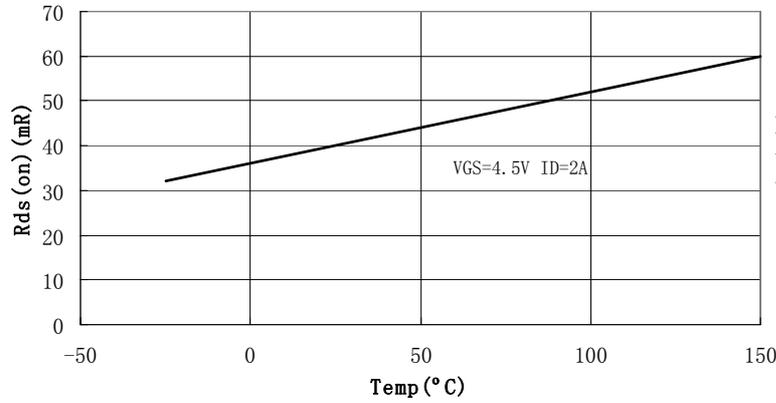


Figure 7. On-Resistance Vs. Junction Temperature

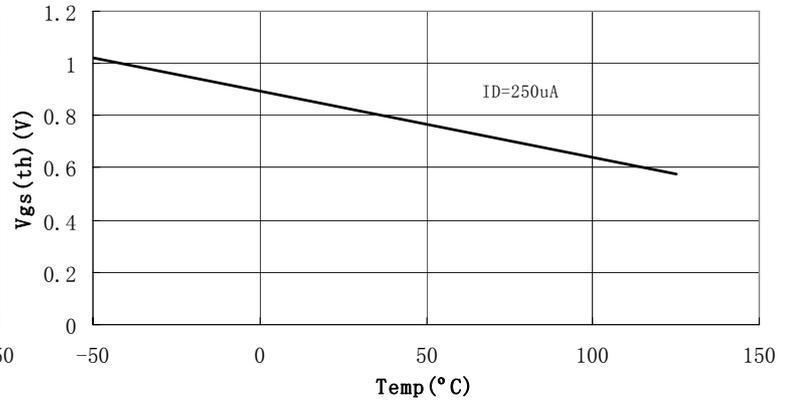


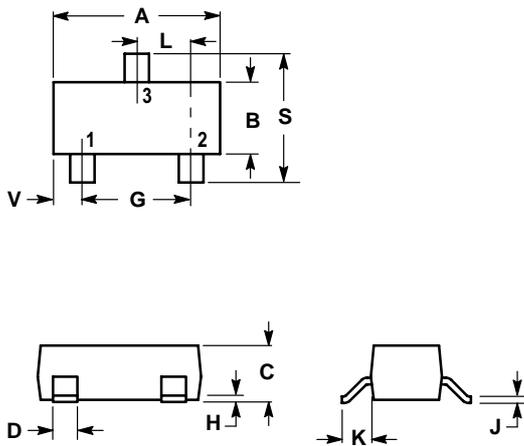
Figure 8. Vth Vs. Junction Temperature

LN2302LT1G

SOT-23

NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M,1982
2. CONTROLLING DIMENSION: INCH.



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.1102	0.1197	2.80	3.04
B	0.0472	0.0551	1.20	1.40
C	0.0350	0.0440	0.89	1.11
D	0.0150	0.0200	0.37	0.50
G	0.0701	0.0807	1.78	2.04
H	0.0005	0.0040	0.013	0.100
J	0.0034	0.0070	0.085	0.177
K	0.0140	0.0285	0.35	0.69
L	0.0350	0.0401	0.89	1.02
S	0.0830	0.1039	2.10	2.64
V	0.0177	0.0236	0.45	0.60

